

APM2320AC-TRL-VB Datasheet

N-Channel 30-V (D-S) MOSFET

PRODUC	RODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
30	0.030 at V _{GS} = 10 V	6.5	4.5 nC			
30	0.033 at $V_{GS} = 4.5 \text{ V}$	6.0	4.5 NC			

FEATURES

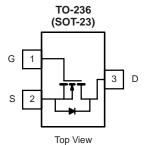
- Halogen-free According to IEC 61249-2-21 Definition
- Trench Power MOSFET
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC

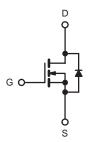


ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

DC/DC Converter





N-Channel MOSFET

ABSOLUTE MAXIMUM RATIN	GS T _A = 25 °C,	unless othe	erwise noted	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	
	T _C = 25 °C		6.5 ^a	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	I _D	6.0	
Continuous Brain Carron (1) = 100 C)	T _A = 25 °C		5.3	
	T _A = 70 °C		5.0	Α
Pulsed Drain Current		I _{DM}	25	
	T _C = 25 °C		1.4	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	0.9 ^{b, c}	
	T _C = 25 °C		1.7	
Maximum Power Dissipation	T _C = 70 °C	P _D	1.1	W
Waximum Tower Dissipation	$T_A = 25 ^{\circ}C$] ' ^D	1.1 ^{b, c}	
	T _A = 70 °C		0.7 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Tempera	ture) ^{d, e}		260	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R_{thJA}	90	115	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	60	75	0/11	

Notes:

- a. Package limited
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 5 s.
- d. Maximum under steady state conditions is 130 $^{\circ}\text{C/W}.$



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					l		
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	ne/Tu		31		> //0/	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA		- 5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	0.7	1.1	2.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μА	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	10			Α	
	_	$V_{GS} = 10 \text{ V}, I_D = 3.2 \text{ A}$		0.030			
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 2.8 \text{ A}$		0.033		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 4.8 A		11		S	
Dynamic ^b							
Input Capacitance	C _{iss}			335			
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		45		pF	
Reverse Transfer Capacitance	C _{rss}			17			
Total Oata Ohanna		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 3.4 \text{ A}$		4.5 6.7	6.7	nC	
Total Gate Charge	Qg			2.1	3.2		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 3.4 \text{ A}$		0.85			
Gate-Drain Charge	Q_{gd}			0.65			
Gate Resistance	R_g	f = 1 MHz	0.8	4.4	8.8	Ω	
Turn-On Delay Time	t _{d(on)}			12	20		
Rise Time	t _r	t_r $V_{DD} = 15 \text{ V}, R_L = 5.6 \Omega$		50	75		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 2.7 A, V_{GEN} = 4.5 V, R_g = 1 Ω		12	20		
Fall Time	t _f			22	35		
Turn-On Delay Time	t _{d(on)}			5	10	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 5.6 Ω		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 2.7 A, V_{GEN} = 10 V, R_g = 1 Ω		10	15		
Fall Time	t _f			5	10		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			1.4		
Pulse Diode Forward Current	I _{SM}				15	A	
Body Diode Voltage	V_{SD}	I _S = 2.7 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			10	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	$I_F = 2.7 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		5	10	nC	
Reverse Recovery Fall Time	ta	i _F = 2.7 A, αί/αι = 100 Α/μ5, 1 _J = 25 °C		6			
Reverse Recovery Rise Time	t _b			4		ns	

Notes

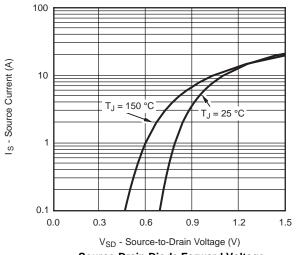
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

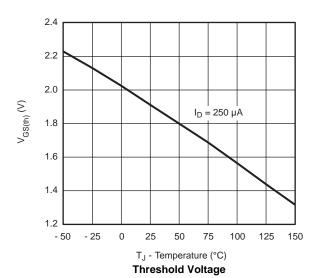


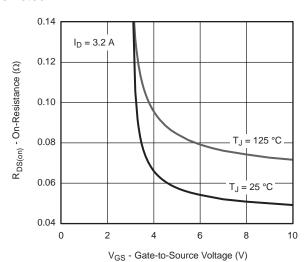




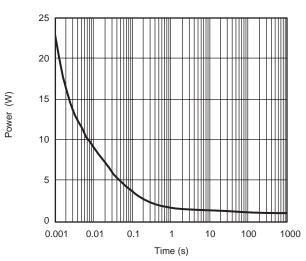




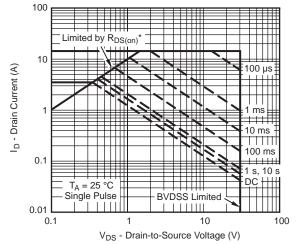




On-Resistance vs. Gate-to-Source Voltage



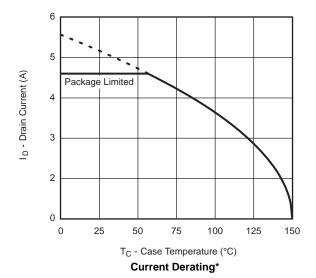
Single Pulse Power

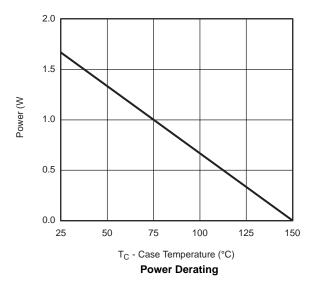


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient



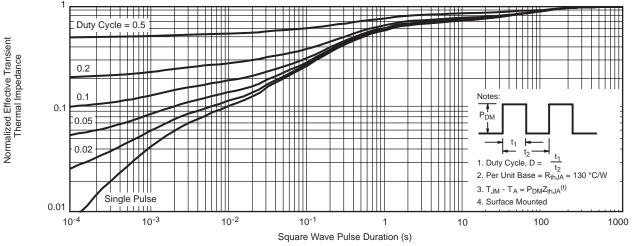




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^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





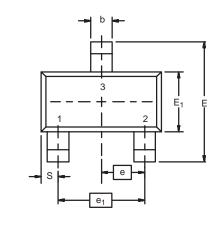
Normalized Thermal Transient Impedance, Junction-to-Ambient

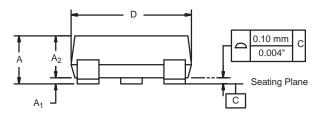


Normalized Thermal Transient Impedance, Junction-to-Foot



SOT-23 (TO-236): 3-LEAD







Dim	MILLIM	IETERS	INCHES		
	Min	Max	Min	Max	
Α	0.89	1.12	0.035	0.044	
A ₁	0.01	0.10	0.0004	0.004	
A ₂	0.88	1.02	0.0346	0.040	
b	0.35	0.50	0.014	0.020	
С	0.085	0.18	0.003	0.007	
D	2.80	3.04	0.110	0.120	
E	2.10	2.64	0.083	0.104	
E ₁	1.20	1.40	0.047	0.055	
е	0.95 BSC		0.0374 Ref		
e ₁	1.90 BSC		0.074	0.0748 Ref	
L	0.40	0.60	0.016	0.024	
L ₁	0.64 Ref		0.025	Ref	
S	0.50 Ref		0.020	Ref	
q	3°	8°	3°	8°	

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DWG: 5479

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RECOMMENDED MINIMUM PADS FOR SOT-23



Recommended Minimum Pads Dimensions in Inches/(mm)

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